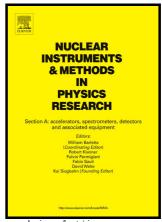
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Simulation of the effects of coated material SEY property on output electron energy distribution and gain of microchannel plates

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ACCEPTED MANUSCRIPT

Simulation of the effects of coated material SEY property on output electron energy distribution and gain of microchannel plates*

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Abstract

To obtain a high spatial resolution of image intensifiers based on microchannel plate (MCP), the long tail in the exit energy distribution of the output electrons (EDOE) is

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